### Nuclear Data Section International Atomic Energy Agency P.O.Box 100, A-1400 Vienna, Austria

#### Memo CP-D/590

Date:	13 October 2009
To:	Distribution
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# Subject:Self-indication and raw dataReference:WP1999-7, CP-D/584

There are 6 entries (40876, 40884, 41151, 41290, 41394, 41426) compiled with SIF in SF6. All were measured by Yu. V. Grigor'ev *et al.* at Dubna and Obninsk reactors.

Because the definition of the self-indication is not very clear from the entry (which was proposed in WP1999-7) and it is closely related to transmission and reaction yield, I would propose to collect explanation of these quantities into a new LEXFOR entry "Transmission and Reaction Yield".

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# **Draft of new LEXFOR entry "Transmission and Reaction Yield"**) **Transmission and Reaction Yield**

**Definition:** Transmission T(E) and reaction yield  $Y_x(E)$  are defined by

$$T(E) = \exp[-n_T \sigma_T(E)]$$
  

$$Y_x(E) = \left[1 - \exp(-n_T \sigma_T(E))\right] \frac{\sigma_x(E)}{\sigma_T(E)} \quad (x = \text{capture, fission etc.})$$

, where,  $n_T$  is the sample thickness in nuclei/barn,  $\sigma_T(E)$  and  $\sigma_x(E)$  are the Dopplerbroadened total cross section and cross section for the channel *x*.

#### **REACTION coding:**

(...(N,TOT)),,TRN) Transmission (...(N,G)...),,TRN,,RYL) Capture yield

#### **Independent variables:**

Incident energy (EN etc.) Sample thickness (THICKNESS) Sample temperature (TEMP)

Units: NO-DIM

Usually these data are reduced from raw data as follows:

$$T = N_T \frac{C'_{in} - B'_{in}}{C'_{out} - B'_{out}} \qquad Y_x = N_x \frac{C'_x - B'_x}{C'_{\varphi} - B'_{\varphi}}$$

, where *in*, *out*, *r* and  $\varphi$  stand for sample-in, sample-out, reaction channel and beam flux measurement,  $N_T$  and  $N_x$  are normalization factors, and *C*' and *B*' denote count and background count corrected for dead time, respectively. In addition, reaction yield from incident particles scattered before inducing the reaction of type *x* should be subtracted from  $Y_x$ . Corrections applied to compiled data should be described under keyword CORRECTION. If appropriate corrections are not applied to data received by compilers, it should be indicated by RAW in SF8. (See **Raw Data**.).

In neutron time-of-flight measurements, the observed value broadened by resolution function is defined by

$$F(T) = \int R(T, E) f(E) dE$$

, where T is the channel number (e.g. time-of-flight channel) and R (T,E) is the resolution function (probability to find outgoing particle having E in T).

#### Transmission ratio and self-indication ratio

Transmission (ratio)  $T_g$  and self-indication (ratio)  $R_{gx}$  are defined as

$$T_{g} = \frac{\int_{g} \varepsilon_{T}(E) \exp[-n_{T}\sigma_{T}(E)]\varphi(E)dE}{\int_{g} \varepsilon_{T}(E)\varphi(E)dE} \sim \frac{\int_{g} \exp[-n_{T}\sigma_{T}(E)]dE/E}{\int_{g} dE/E}$$
$$R_{gx} = \frac{\int_{g} \varepsilon_{x}(E_{\gamma})n_{x}\sigma_{x}(E) \exp[-n_{T}\sigma_{T}(E)]\varphi(E)dE}{\int_{g} \varepsilon_{x}(E_{\gamma})n_{x}\sigma_{x}(E)\varphi(E)dE} \sim \frac{\int_{g} \sigma_{x}(E) \exp[-n_{T}\sigma_{T}(E)]dE/E}{\int_{g} \sigma_{x}(E) dE/E}$$

, where  $\varepsilon_T(E)$  and  $\varepsilon_x(E)$  give efficiencies detectors for transmission and reaction yield measurements,  $n_x$  gives the sample thickness of the thin reaction target,  $\varphi(E)$  gives spectrum of incoming particles. Integration is performed over a given energy range of the energy group g. The approximation ~ is applied when the efficiencies are regarded as constants and the spectrum is proportional to 1/E. These ratios can be used to derive self-shielding factors in reactor physics [1,2].

#### **REACTION coding**:

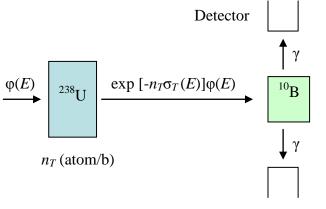
((N,TOT)),,TRN,,SPA)	Transmission (ratio)
((N,G)),,SIF,,SPA)	Self-indication (ratio) for capture

#### **Independent variables:**

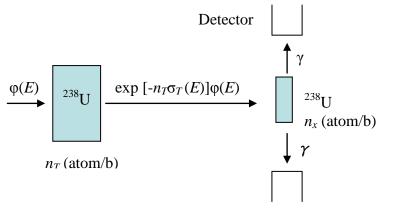
Upper and lower boundary of incident energy (EN-MIN, EN-MAX) Sample thickness (THICKNESS) Sample temperature (TEMP)

Units: NO-DIM

Spectrum should be explained under INC-SPECT.



(a) Transmission measurement for <sup>238</sup>U



(b) Self-indication measurement for  $^{238}$ U

## **References**

- [1] H. Oigawa et al., J. Nucl. Sci. Technol. 28 (1991) 879
- [2] T. Bakalov *et al.*, Proc. of Int. Conf. on Nuclear Cross Sections for Technology, Knoxville, Tennessee, 22 - 26 Oct 1979, p692.